

# SN54276, SN74276 QUADRUPLE J-K FLIP-FLOPS

SDLS091

OCTOBER 1976 - REVISED MARCH 1988

- Four J-K Flip-Flops in a Single Package . . . Can Reduce FF Package Count by 50%
- Separate Negative-Edge-Triggered Clocks with Hysteresis . . . Typically 200 mV
- Typical Clock Input Frequency . . . 50 MHz
- Fully Buffered Outputs

### description

These quadruple TTL J-K flip-flops incorporate a number of third-generation IC features that can simplify system design and reduce flip-flop package count by up to 50%. They feature hysteresis at each clock input, fully buffered outputs, and direct clear capability, and are presettable through a buffer that also features an input hysteresis loop. The negative-edge-triggering clocks are directly compatible with earlier Series 54/74 single and dual pulse-triggered flip-flops. These circuits can be used to emulate D- or T-type flip-flops by hard-wiring the inputs, or to implement asynchronous sequential functions.

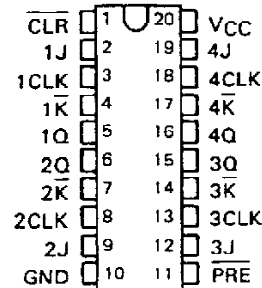
The SN54276 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ ; the SN74276 is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

FUNCTION TABLE (EACH FLIP-FLOP)

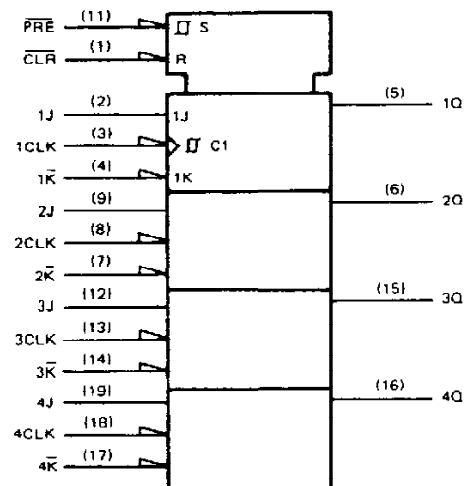
COMMON INPUTS		INPUTS			OUTPUT
PRE	CLR	CLK	J	$\bar{K}$	Q
L	H	X	X	X	H
H	L	X	X	X	L
L	L	X	X	X	H <sup>†</sup>
H	H	↓	L	H	Q <sub>0</sub>
H	H	↓	H	H	H
H	H	↓	L	L	L
H	H	↓	H	L	TOGGLE
H	H	H	X	X	Q <sub>0</sub>

<sup>†</sup> This configuration is nonstable; that is, it may not persist when preset and clear return to their inactive (high) level.

SN54276 . . . J PACKAGE  
SN74276 . . . N PACKAGE  
(TOP VIEW)



### logic symbol<sup>‡</sup>



<sup>‡</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

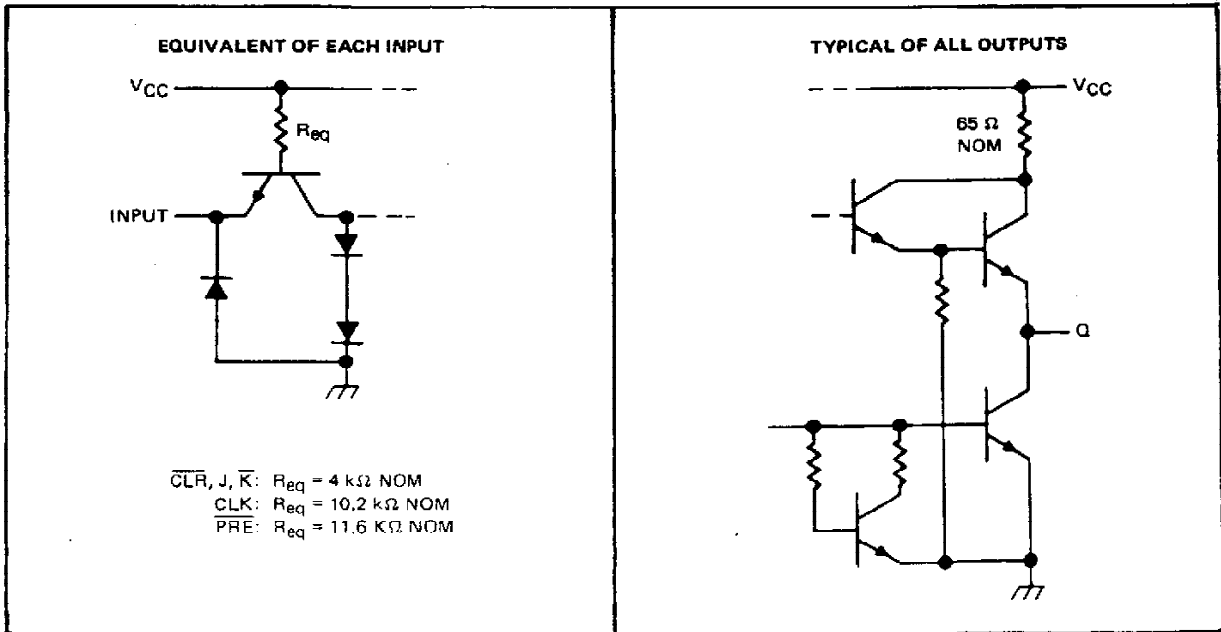
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**SN54276, SN74276  
QUADRUPLE J-K FLIP-FLOPS**

**schematics of inputs and outputs**



**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)**

Supply voltage, $V_{CC}$ (see Note 1) .....	7 V
Input voltage .....	5.5 V
Operating free-air temperature range: SN54276 .....	-55°C to 125°C
SN74276 .....	0°C to 70°C
Storage temperature range .....	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

# SN54276, SN74276 QUADRUPLE J-K FLIP-FLOPS

## recommended operating conditions

	SN54276			SN74276			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, $V_{CC}$	4.5	5	5.5	4.75	5	5.25	V
High-level output current, $I_{OH}$			-800			-800	$\mu A$
Low-level output current, $I_{OL}$			16			16	mA
Clock frequency	0		35	0		35	MHz
Pulse width, $t_w$	Clock high	13.5		13.5			ns
	Clock low	15		15			
	Preset or clear low	12		12			
Setup time, $t_{SU}$	J, K inputs	3↓		3↓			ns
	Clear and preset inactive state	10↓		10↓			
Input hold time, $t_H$		10↓		10↓			ns
Operating free-air temperature, $T_A$		-55	125			70	$^{\circ}C$

↓ The arrow indicates that the falling edge of the clock pulse is used for reference.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
$V_{IH}$ High-level input voltage		2			V
$V_{IL}$ Low-level input voltage				0.8	V
$V_{IK}$ Input clamp voltage	$V_{CC} = \text{MIN}$ , $I_I = -12 \text{ mA}$			-1.5	V
$V_{OH}$ High-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ , $V_{IL} = 0.8 \text{ V}$ , $I_{OH} = -800 \mu A$	2.4	3.4		V
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}$ , $V_{IH} = 2 \text{ V}$ , $V_{IL} = 0.8 \text{ V}$ , $I_{OL} = 16 \text{ mA}$		0.2	0.4	V
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}$ , $V_I = 5.5 \text{ V}$			1	mA
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}$ , $V_I = 2.4 \text{ V}$			40	$\mu A$
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}$ , $V_I = 0.4 \text{ V}$			-1.6	mA
$I_{OS}$ Short-circuit output current§	$V_{CC} = \text{MAX}$	-30		-85	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$		60	81	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}C$ .

§ Not more than one output should be shorted at a time.

## switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}C$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{max}$ Maximum clock frequency		35	50		MHz
$t_{PLH}$ Propagation delay time, low-to-high-level output from preset	$C_L = 15 \text{ pF}$ , $R_L = 400 \Omega$ , See Note 2		15	25	ns
$t_{PHL}$ Propagation delay time, high-to-low-level output from clear			18	30	ns
$t_{PLH}$ Propagation delay time, low-to-high level output from clock			17	30	ns
$t_{PHL}$ Propagation delay time, high-to-low level output from clock			20	30	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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